IQ-5310

Wavelength Meter



- Absolute wavelength accuracy: ±0.01 nm
- Simultaneous display of central wavelength and total power
- Wavelength display resolution: 0.001 nm
- Integrated user-calibration capability



Unsurpassed Accuracy

The IQ-5310 Wavelength Meter is the ideal modular instrument for measuring the central wavelength and frequency of a single incoming laser signal. It is perfectly suited for determining central wavelength shifts in conditions where the temperature, current, and power may vary. The module also allows for accurate laser diode and

transmitter characterization as well as simple wavelength calibration of other instruments, including optical spectrum analyzers (OSAs) and tunable laser sources. The IQ-5310 is indispensable if you need to control the drift of dense WDM channels for transmission system qualification.

The module operates in two different modes to display its

evaluates the laser linewidth and determines the number of

digits to be shown. In Full mode, a 0.001 nm resolution is

always displayed. The coherence length of a laser beam

results: Auto and Full. In Auto mode, the instrument

Basic Operation

The IQ-5310 measures wavelengths from the visible to the near-infrared range (600 to 1700 nm). The instrument is designed around a Michelson interferometer. The scanning distance of the interferometer's mirror is first calibrated with a reference laser that has a central wavelength value at least 10 times more accurate than the specified accuracy of the instrument. The IQ-5310 is then ready to perform its

high-fidelity test measurements.

When a signal, coupled into an optical fiber, first enters the instrument, it produces sinusoidal

Effective linewidth	Wavelength accuracy	Display resolution in Average mode
<10 GHz	±0.01 nm	0.001 nm
≈100 GHz	±0.1 nm	0.01 nm
≈1 THz	±1 nm	0.1 nm

plays a crucial role when using an interferometer to measure wavelength. Readings are more accurate and have the highest resolution with Average mode

The highest resolution with narrow linewidths

The IQ-5310 is initially calibrated with a reference source traceable to

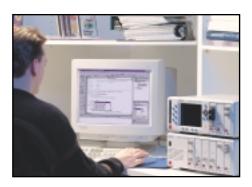
(<10 GHz).

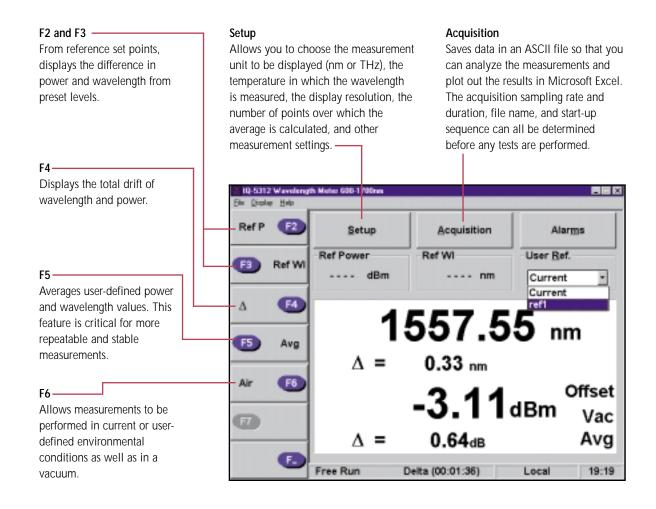
NIST. To save time, ensure optimum accuracy, and decrease costs, you can calibrate the instrument yourself with a stabilized HeNe laser or a DFB laser diode. EXFO also provides all calibration services upon request.

interference fringes. By counting the number of peaks detected during one mirror sweep of the interferometer, the IQ-5310 precisely measures the wavelength or frequency of the incoming signal. Pressure and temperature are constantly monitored to obtain wavelengths in a vacuum and various air conditions. When measuring optical power, the module automatically compensates for the detector's spectral responsitivity.

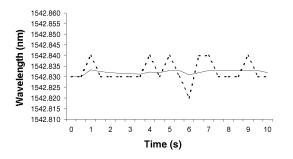
The IQ Concept

EXFO has integrated highly precise wavelength measurement technology into its versatile IQ-200 Optical Test System. With the test platform's powerful capabilities and user-friendly visual development environments, such as Visual Basic and Delphi, the IQ-5310 can be integrated quickly and easily into your automated optical test system.





Real-time and Average mode



Average

In Average mode, a resolution of 0.001 nm can be attained.

---- Real-time (2 Hz) value

— Progressive average value



Alarm

The alarm warns you with a beeping noise if the wavelength or power falls outside predefined limits. For long-term monitoring, the exceeded times and limits are logged.

SPECIFICATIONS

Model		IQ-5312	
Spectral range (nm)		600 to 1700	
Photodetector type ¹		InGaAs	
Power input range (dBm)		+10 to -30	
Optical input		singlemode fiber	
Wavelength display resolution ² (nm)		0.001	
Absolute wavelength accuracy ³ (nm)		±0.03/±0.01 ⁴	
Wavelength repeatability₅ (nm)		±0.02	
Power display resolution (dB)		0.01	
Absolute power accuracy ⁶ (dB)		±0.25	
Power measurement linearity ⁷ (dB)		<0.1	
Optical return loss (dB)	typical	35	
Polarization dependent loss (dB)	at 1310 nm	<0.25	
	at 1550 nm	< 0.35	
Sampling rate (Hz)		2	
Averaging		up to 1000 samples	

GENERAL SPECIFICATIONS

Size		12 x 3.8 x 26.2 cm	4³/ ₄ x 1¹/ ₂ x 10¹/ ₃ in.
Temperature	operating	10° to 40°C	5° to 104°F
	storage	-40° to 70°C	-40° to 158°F
Relative humidity		0 to 95% non-condensing	

NOTES

- 1. A wavelength meter (with similar specifications) equipped with a silicon detector (IQ-5311) is also available upon request for a shorter wavelength measurement range.
- 2. In averaging mode only. In real-time mode: 0.01 nm.
- 3. Due to the acquisition system's bandwidth, the presence of a low-frequency modulated signal can be interpreted as an erroneous wavelength.
- 4. After calibration with an external reference source or at 25°C.
- 5. Confidence level of 95% over one hour.
- 6. 1550 ±30 nm, 1310 ±20 nm at 25°C. Does not include connector repeatability.
- 7. Between -20 dBm and +10 dBm.

EXFO is certified ISO 9001 and attests to the quality of its products. These products are accompanied by a 24-month warranty and an excellent after-sales support service.

This device complies with Part 15 of the FCC Rules. Operation is subject to the following two conditions: (1) this device may not cause harmful interference, and (2) this device must accept any interference received, including interference that may cause undesired operation.

EXFO has made every effort to ensure that the information contained in this brochure is accurate. However, we accept no responsibility for any errors or omissions, and we reserve the right to modify design, characteristics, and products at any time without obligation.

Contact EXFO for prices and availability or to obtain the phone number of your local EXFO distributor.

STANDARD ACCESSORIES

Instruction manual and Declaration of Conformity

ORDERING INFORMATION

IQ-5312-<u>XX</u>

Connector code

58 = FC/APC narrow key

89 = FC/UPC

EI = UPC Universal Interface

EA = APC Universal Interface

The fixed base-plate (El or EA) must be ordered with a removable universal connector adapter (EUI-XX). Please specify one EUI from the following list:





1 800 663-3936 info@exfo.com www.exfo.com



CORPORATE HEADQUARTERS: 465 Godin Avenue, Vanier QC G1M 3G7, Canada Tel.: (418) 683-0211 Fax: (418) 683-2170 EXFO AMERICA: 903 North Bowser, Suite 360, Richardson, TX, 75081, USA Tel.: 1 800 663-3936 Fax: (972) 907-2297 EXFO EUROPE: Centre d'Affaires Les Metz, 100, rue Albert Calmette, 78353 Jouy-en-Josas, France Tel.: +33 1 34 63 00 20 Fax: +33 1 34 65 90 93